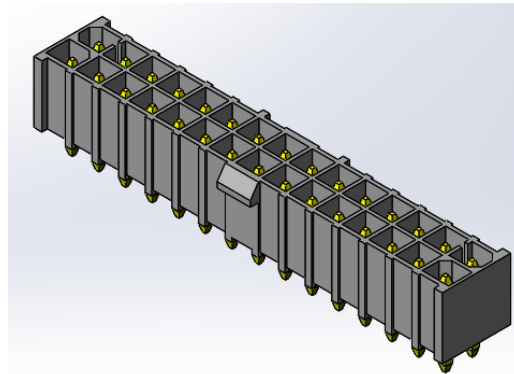
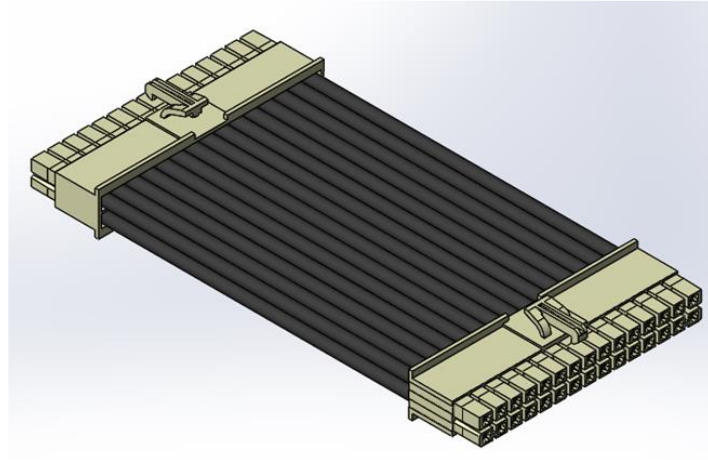




Project Number: Design Qualification Test Report	Tracking Code: 2041063_Report_Rev_3
Requested by: Kaelin Love	Date: 7/28/2022
Part #: PMSD-15-18-K-12.00-D-LUS/IPBT-115-H1-T-D-K	
Part description: PMSD/IPBT	Tech: John Crawford
Test Start: 11/29/2019	Test Completed: 1/3/2020



DESIGN QUALIFICATION TEST REPORT
PMSD/IPBT
PMSD-15-18-K-12.00-D-LUS/IPBT-115-H1-T-D-K

Tracking Code: 2041063_Report_Rev_3	Part #: PMSD-15-18-K-12.00-D-LUS/IPBT-115-H1-T-D-K
Part description: PMSD/IPBT	

REVISION HISTORY

DATA	REV.NUM.	DESCRIPTION	ENG
4/13/2020	1	Design Qualification Testing	KH
7/9/2021	2	Add the latch pull test data from request 2277951	KH
7/27/2022	3	Add the mating-unmating basic test data from request CR-687201	KH

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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SCOPE

To perform the following tests: Design Qualification test. Please see test plan.

APPLICABLE DOCUMENTS

Standards: EIA Publication 364

TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCR and DWV/IR testing were cleaned according to CO-SC-WI-3029.
- 4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
- 5) The automated procedure is used with aqueous compatible soldering materials.
- 6) Parts not intended for testing LLCR and DWV/IR are visually inspected and cleaned if necessary.
- 7) Any additional preparation will be noted in the individual test sequences.
- 8) Solder Information: Lead Free
- 9) Samtec Test PCBs used: PCB-109948-TST/PCB-109949-TST/PCB-109950-TST

FLOWCHARTS

Gas Tight

Group 1

PMSD-15-18-K-06.00-S-XXX

IPBT-115-H1-T-D-K

8 Assemblies

Step	Description
------	-------------

- | | |
|----|--|
| 1. | LLCR ⁽²⁾ |
| 2. | Gas Tight ⁽¹⁾ |
| 3. | LLCR ⁽²⁾
Max Delta = 15 mOhm |

(1) Gas Tight = EIA-364-36

(2) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

Normal Force

Group 1

PMSD-15-18-K-12.00-D-LUS

IPBT-115-H1-T-D-K

8 Contacts Minimum

Signal Without Thermals

Step	Description
------	-------------

- | | |
|----|---|
| 1. | Contact Gaps |
| 2. | Normal Force ⁽¹⁾
Deflection = 0.013 "
Expected Force at Max Deflection = 208 g |

Group 2

PMSD-15-18-K-12.00-D-LUS

IPBT-115-H1-T-D-K

8 Contacts Minimum

Signal With Thermals

Step	Description
------	-------------

- | | |
|----|---|
| 1. | Contact Gaps |
| 2. | Thermal Age ⁽²⁾ |
| 3. | Contact Gaps |
| 4. | Normal Force ⁽¹⁾
Deflection = 0.013 "
Expected Force at Max Deflection = 208 g |

(1) Normal Force = EIA-364-04

(2) Thermal Age = EIA-364-17

Test Condition = 4 (105°C)

Time Condition = B (250 Hours)

FLOWCHARTS Continued**Thermal Aging**Group 1

PMSD-15-18-K-06.00-S-XXX

IPBT-115-H1-T-D-K

8 Assemblies

Step	Description
1.	Contact Gaps
2.	Mating/Unmating Force ⁽²⁾
3.	LLCR ⁽¹⁾
4.	Thermal Age ⁽³⁾
5.	LLCR ⁽¹⁾ Max Delta = 15 mOhm
6.	Mating/Unmating Force ⁽²⁾
7.	Contact Gaps

(1) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

(2) Mating/Unmating Force = EIA-364-13

(3) Thermal Age = EIA-364-17

Test Condition = 4 (105°C)

Time Condition = B (250 Hours)

FLOWCHARTS Continued**Mating/Unmating/Durability**

Group 1
PMSD-15-18-K-06.00-S-XXX
IPBT-115-H1-T-D-K
8 Assemblies

Step	Description
1.	Contact Gaps
2.	LLCR ⁽²⁾
3.	Mating/Unmating Force ⁽³⁾
4.	Cycles Quantity = 25 Cycles
5.	Mating/Unmating Force ⁽³⁾
6.	Contact Gaps
7.	LLCR ⁽²⁾ Max Delta = 15 mOhm
8.	Thermal Shock ⁽⁴⁾
9.	LLCR ⁽²⁾ Max Delta = 15 mOhm
10.	Humidity ⁽¹⁾
11.	LLCR ⁽²⁾ Max Delta = 15 mOhm
12.	Mating/Unmating Force ⁽³⁾

Group 2
PMSD-02-18-K-06.00-S-XXX
IPBT-102-H1-T-D-K
8 Assemblies

Step	Description
1.	Contact Gaps
2.	Mating/Unmating Force ⁽³⁾
3.	Cycles Quantity = 25 Cycles
4.	Mating/Unmating Force ⁽³⁾
5.	Cycles Quantity = 25 Cycles
6.	Mating/Unmating Force ⁽³⁾
7.	Cycles Quantity = 25 Cycles
8.	Mating/Unmating Force ⁽³⁾
9.	Cycles Quantity = 25 Cycles
10.	Mating/Unmating Force ⁽³⁾

Group 3
PMSD-08-18-K-06.00-S-XXX
IPBT-108-H1-T-D-K
8 Assemblies

Step	Description
1.	Contact Gaps
2.	Mating/Unmating Force ⁽³⁾
3.	Cycles Quantity = 25 Cycles
4.	Mating/Unmating Force ⁽³⁾
5.	Cycles Quantity = 25 Cycles
6.	Mating/Unmating Force ⁽³⁾
7.	Cycles Quantity = 25 Cycles
8.	Mating/Unmating Force ⁽³⁾
9.	Cycles Quantity = 25 Cycles
10.	Mating/Unmating Force ⁽³⁾

(1) Humidity = EIA-364-31

Test Condition = B (240 Hours)

Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)

Test Exceptions: ambient pre-condition and delete steps 7a and 7b

(2) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

(3) Mating/Unmating Force = EIA-364-13

(4) Thermal Shock = EIA-364-32

Exposure Time at Temperature Extremes = 1/2 Hour

Method A, Test Condition = I (-55°C to +85°C)

Test Duration = A-3 (100 Cycles)

FLOWCHARTS Continued**IR/DWV****Pin-to-Pin**Group 1

PMSD-15-18-K-06.00-S-XXX

IPBT-115-H1-T-D-K

2 Assemblies

Step	Description
1.	IR ⁽³⁾
2.	DWV at Test Voltage ⁽¹⁾ Test Voltage = 900 V
3.	Thermal Shock ⁽⁴⁾
4.	IR ⁽³⁾
5.	DWV at Test Voltage ⁽¹⁾ Test Voltage = 900 V
6.	Humidity ⁽²⁾
7.	IR ⁽³⁾
8.	DWV at Test Voltage ⁽¹⁾ Test Voltage = 900 V

Row-to-RowGroup 2

PMSD-15-18-K-06.00-S-XXX

IPBT-115-H1-T-D-K

2 Assemblies

Step	Description
1.	IR ⁽³⁾
2.	DWV at Test Voltage ⁽¹⁾ Test Voltage = 900 V
3.	Thermal Shock ⁽⁴⁾
4.	IR ⁽³⁾
5.	DWV at Test Voltage ⁽¹⁾ Test Voltage = 900 V
6.	Humidity ⁽²⁾
7.	IR ⁽³⁾
8.	DWV at Test Voltage ⁽¹⁾ Test Voltage = 900 V

-
- (1) DWV at Test Voltage = EIA-364-20
Test Condition = 1 (Sea Level)
DWV test voltage is equal to 75% of the lowest breakdown voltage
Test voltage applied for 60 seconds
- (2) Humidity = EIA-364-31
Test Condition = B (240 Hours)
Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)
Test Exceptions: ambient pre-condition and delete steps 7a and 7b
- (3) IR = EIA-364-21
Test Condition = 500 Vdc, 2 Minutes Max
- (4) Thermal Shock = EIA-364-32
Exposure Time at Temperature Extremes = 1/2 Hour
Method A, Test Condition = I (-55°C to +85°C)
Test Duration = A-3 (100 Cycles)

FLOWCHARTS Continued**Current Carrying Capacity**Group 1

PMSD-15-18-K-12.00-D-LUS
IPBT-115-H1-T-D-K
2 Pins Powered
Signal

Step Description

1. CCC ⁽¹⁾
Rows = 2
Number of Positions = 1

Group 2

PMSD-15-18-K-12.00-D-LUS
IPBT-115-H1-T-D-K
4 Pins Powered
Signal

Step Description

1. CCC ⁽¹⁾
Rows = 2
Number of Positions = 2

Group 3

PMSD-15-18-K-12.00-D-LUS
IPBT-115-H1-T-D-K
6 Pins Powered
Signal

Step Description

1. CCC ⁽¹⁾
Rows = 2
Number of Positions = 3

Group 4

PMSD-15-18-K-12.00-D-LUS
IPBT-115-H1-T-D-K
8 Pins Powered
Signal

Step Description

1. CCC ⁽¹⁾
Rows = 2
Number of Positions = 4

Group 5

PMSD-15-18-K-12.00-D-LUS
IPBT-115-H1-T-D-K
30 Pins Powered
Signal

Step Description

1. CCC ⁽¹⁾
Rows = 2
Number of Positions = 15

(1) CCC = EIA-364-70

Method 2, Temperature Rise Versus Current Curve

(TIN PLATING) - Tabulate calculated current at RT, 65°C, 75°C and 95°C after derating 20% and based on 105°C

(GOLD PLATING) - Tabulate calculated current at RT, 85°C, 95°C and 115°C after derating 20% and based on 125°C

FLOWCHARTS Continued**Mechanical Shock/Random Vibration/LLCR**Group 1

PMSD-15-18-K-12.00-S-XXX

IPBT-115-H1-T-D-K

8 Assemblies

Step Description

1. LLCR ⁽¹⁾
2. Mechanical Shock ⁽²⁾
3. Random Vibration ⁽³⁾
4. LLCR ⁽¹⁾
Max Delta = 15 mOhm

(1) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

(2) Mechanical Shock = EIA-364-27

Test Condition = C (100 G Peak, 6 milliseconds, Half Sine)

Number of Shocks = 3 Per Direction, Per Axis, 18 Total

(3) Random Vibration = EIA-364-28

Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

Mechanical Shock/Random Vibration/Event DetectionGroup 1

PMSD-15-18-K-12.00-S-XXX

IPBT-115-H1-T-D-K

60 Points

Step Description

1. Nanosecond Event Detection
(Mechanical Shock) ⁽¹⁾
2. Nanosecond Event Detection
(Random Vibration) ⁽²⁾

(1) Nanosecond Event Detection (Mechanical Shock)

Use EIA-364-87 for Nanosecond Event Detection:

Test Condition = F (50 nanoseconds at 10 ohms)

Use EIA-364-27 for Mechanical Shock:

Test Condition = C (100 G Peak, 6 milliseconds, Half Sine)

Number of Shocks = 3 Per Direction, Per Axis, 18 Total

(2) Nanosecond Event Detection (Random Vibration)

Use EIA-364-87 for Nanosecond Event Detection:

Test Condition = F (50 nanoseconds at 10 ohms)

Use EIA-364-28 for Random Vibration:

Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

FLOWCHARTS Continued**Cable Pull**Group 1

PMSD-15-18-K-12.00-D-LUS

IPBT-115-H1-T-D-K

5 Assemblies

0 Degrees

Step Description1. Cable Pull ⁽¹⁾Group 2

PMSD-15-18-K-12.00-D-LUS

IPBT-115-H1-T-D-K

5 Assemblies

90 Degrees

Step Description1. Cable Pull ⁽¹⁾Group 3

PMSD-15-18-K-12.00-D-LUS

IPBT-115-H1-T-D-K

5 Assemblies

90 Degrees Transverse

Step Description1. Cable Pull ⁽¹⁾

(1) Cable Pull = EIA-364-38

Measure and Record Force Required to Failure

Failure = Discontinuity >1 microsecond at 10 ohms

Cable FlexGroup 1

PMSD-15-18-K-12.00-D-LUS

IPBT-115-H1-T-D-K

8 Assemblies

Flat Cable

Step Description1. IR ⁽³⁾2. DWV at Test Voltage ⁽²⁾

Test Voltage = 900 V

3. Cable Flex ⁽¹⁾

4. Visual Inspection

5. IR ⁽³⁾6. DWV at Test Voltage ⁽²⁾

Test Voltage = 900 V

(1) Cable Flex = EIA-364-41

Circular Jacket Cable - to be tested 90° each direction (180° total)

Flat Cable - to be tested 70° each direction (140° total)

Monitor continuity during flex testing

Failure = Discontinuity >1 microsecond at 10 ohms

(2) DWV at Test Voltage = EIA-364-20

Test Condition = 1 (Sea Level)

DWV test voltage is equal to 75% of the lowest breakdown voltage

Test voltage applied for 60 seconds

(3) IR = EIA-364-21

Test Condition = 500 Vdc, 2 Minutes Max

FLOWCHARTS Continued**Latch Pull Test**Group 1

PMSD-15-18-K-06.00-S-XXX

T-32046-02

8 Assemblies

Step Description

1. Cycles
Quantity = 250 Cycles
Note: Mate with T-32046-02 until latch fully engages. Actuate latch to unmate. Repeat until required cycles are completed.
2. Cable Pull ⁽¹⁾ - Non Standard
Note: Mate with T-32046-02 until latch fully engages. Apply increased pull force until the the latch fractures or disengages.

Group 2

PMSD-15-18-K-06.00-S-XXX

T-32046-02

8 Assemblies

With Thermal Age

Step Description

1. Thermal Age ⁽²⁾
2. Cycles
Quantity = 250 Cycles
Note: Mate with T-32046-02 until latch fully engages. Actuate latch to unmate. Repeat until required cycles are completed.
3. Cable Pull ⁽¹⁾ - Non Standard
Note: Mate with T-32046-02 until latch fully engages. Apply increased pull force until the the latch fractures or disengages.

 (1) Cable Pull = Other

Measure and Record Force Required to Failure

Failure = Mechanical failure

(2) Thermal Age = EIA-364-17

Test Condition = 4 (105°C)

Time Condition = B (250 Hours)

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

THERMAL:

- 1) EIA-364-17, *Temperature Life with or without Electrical Load Test Procedure for Electrical Connectors*.
- 2) Test Condition at 105° C.
- 3) Test Time Condition B for 250 hours.
- 4) All test samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

THERMAL SHOCK:

- 1) EIA-364-32, *Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors*.
- 2) Test Condition I: -55°C to +85°C
- 3) Test Time: ½ hour dwell at each temperature extreme
- 4) Number of Cycles: 100
- 5) All test samples are pre-conditioned at ambient.
- 6) All test samples are exposed to environmental stressing in the mated condition.

HUMIDITY:

- 1) Reference document: EIA-364-31, *Humidity Test Procedure for Electrical Connectors*.
- 2) Test Condition B, 240 Hours.
- 3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
- 4) All samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

MECHANICAL SHOCK (Specified Pulse):

- 1) Reference document: EIA-364-27, *Mechanical Shock Test Procedure for Electrical Connectors*
- 2) Test Condition G
- 3) Peak Value: 100 G
- 4) Duration: 6 Milliseconds
- 5) Wave Form: Sawtooth
- 6) Velocity: 12.3 ft/s
- 7) Number of Shocks: 3 Shocks / Direction, 3 Axis (18 Total)

VIBRATION:

- 1) Reference document: EIA-364-28, *Vibration Test Procedure for Electrical Connectors*
- 2) Test Condition V, Letter B
- 3) Power Spectral Density: 0.04 G² / Hz
- 4) G 'RMS': 7.56
- 5) Frequency: 50 to 2000 Hz
- 6) Duration: 2.0 Hours per axis (3 axis total)

NANOSECOND-EVENT DETECTION:

- 1) Reference document: EIA-364-87, *Nanosecond-Event Detection for Electrical Connectors*
- 2) Prior to test, the samples were characterized to assure the low nanosecond event being monitored will trigger the detector.
- 3) After characterization it was determined the test samples could be monitored for 50 nanosecond events

MATING/UNMATING:

- 1) Reference document: EIA-364-13, *Mating and Unmating Forces Test Procedure for Electrical Connectors*.
- 2) The full insertion position was to within 0.003" to 0.004" of the plug bottoming out in the receptacle to prevent damage to the system under test.
- 3) One of the mating parts is secured to a floating X-Y table to prevent damage during cycling.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

NORMAL FORCE (FOR CONTACTS TESTED OUTSIDE THE HOUSING):

- 1) Reference document: EIA-364-04, *Normal Force Test Procedure for Electrical Connectors*.
- 2) The contacts shall be tested in the loose state, *not* inserted in connector housing.
- 3) The contacts shall be prepared to allow access to the spring member at the same attitude and deflection level as would occur in actual use.
- 4) In the event that portions of the contact prevent insertion of the test probe and/or deflection of the spring member under evaluation, said material shall be removed leaving the appropriate contact surfaces exposed.
- 5) In the case of multi-tine contacts, each tine shall be tested independently on separate samples as required.
- 6) The connector housing shall be simulated, if required, in order to provide an accurate representation of the actual contact system performance.
- 7) A holding fixture shall be fashioned to allow the contact to be properly deflected.
- 8) Said holding fixture shall be mounted on a floating, adjustable, X-Y table on the base of the Dillon TC², computer controlled test stand with a deflection measurement system accuracy of 5 μ m (0.0002").
- 9) The probe shall be attached to a Dillon P/N 49761-0105, 5 N (1.1 Lb) load cell providing an accuracy of $\pm$ 0.2%.
- 10) The nominal deflection rate shall be 5 mm (0.2")/minute.
- 11) Unless otherwise noted a minimum of five contacts shall be tested.
- 12) The force/deflection characteristic to load and unload each contact shall be repeated five times.
- 13) The system shall utilize the TC² software in order to acquire and record the test data.
- 14) The permanent set of each contact shall be measured within the TC² software.
- 15) The acquired data shall be graphed with the deflection data on the X-axis and the force data on the Y-axis and a print out will be stored with the Tracking Code paperwork.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

LLCR:

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
 - a. $\leq +5.0$ mOhms: -----Stable
 - b. $+5.1$ to $+10.0$ mOhms: -----Minor
 - c. $+10.1$ to $+15.0$ mOhms: -----Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: -----Marginal
 - e. $+50.1$ to $+1000$ mOhms: -----Unstable
 - f. $>+1000$ mOhms: -----Open Failure

GAS TIGHT:

To provide method for evaluating the ability of the contacting surfaces in preventing penetration of harsh vapors which might lead to oxide formation that may degrade the electrical performance of the contact system.

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
 - a. $\leq +5.0$ mOhms: -----Stable
 - b. $+5.1$ to $+10.0$ mOhms: -----Minor
 - c. $+10.1$ to $+15.0$ mOhms: -----Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: -----Marginal
 - e. $+50.1$ to $+1000$ mOhms: -----Unstable
 - f. $>+1000$ mOhms: -----Open Failure
- 4) Procedure:
 - a. Reference document: EIA-364-36, *Test Procedure for Determination of Gas-Tight Characteristics for Electrical Connectors, Sockets and/or Contact Systems*.
 - b. Test Conditions:
 - i. Class II--- Mated pairs of contacts assembled to their plastic housings.
 - ii. Reagent grade Nitric Acid shall be used of sufficient volume to saturate the test chamber
 - iii. The ratio of the volume of the test chamber to the surface area of the acid shall be 10:1.
 - iv. The chamber shall be saturated with the vapor for at least 15 minutes before samples are added.
 - v. Exposure time, 55 to 65 minutes.
 - vi. The samples shall be no closer to the chamber walls than 1 inches and no closer to the surface of the acid than 3 inches.
 - vii. The samples shall be dried after exposure for a minimum of 1 hour.
 - viii. Drying temperature 50° C
 - ix. The final LLCR shall be conducted within 1 hour after drying.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

INSULATION RESISTANCE (IR):

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

- 1) PROCEDURE:
 - a. Reference document: EIA-364-21, *Insulation Resistance Test Procedure for Electrical Connectors*.
 - b. Test Conditions:
 - i. Between Adjacent Contacts or Signal-to-Ground
 - ii. Electrification Time 2.0 minutes
 - iii. Test Voltage (500 VDC) corresponds to calibration settings for measuring resistances.
- 2) MEASUREMENTS:
- 3) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 5000 megohms.

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and other similar phenomenon. Separate samples are used to evaluate the effect of environmental stresses so not to influence the readings from arcing that occurs during the measurement process.

- 1) PROCEDURE:
 - a. Reference document: EIA-364-20, *Withstanding Voltage Test Procedure for Electrical Connectors*.
 - b. Test Conditions:
 - i. Between Adjacent Contacts or Signal-to-Ground
 - ii. Barometric Test Condition 1
 - iii. Rate of Application 500 V/Sec
 - iv. Test Voltage (VAC) until breakdown occurs
- 2) MEASUREMENTS/CALCULATIONS
 - a. The breakdown voltage shall be measured and recorded.
 - b. The dielectric withstanding voltage shall be recorded as 75% of the minimum breakdown voltage.
 - c. The working voltage shall be recorded as one-third (1/3) of the dielectric withstanding voltage (one-fourth of the breakdown voltage).

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

CABLE PULL:

- 1) Secure cable near center and pull on connector
 - a. At 0°, in-line with cable
 - b. At 90°, in-line with cable



Fig. 1

0° Connector pull



Fig. 2

90° Connector pull

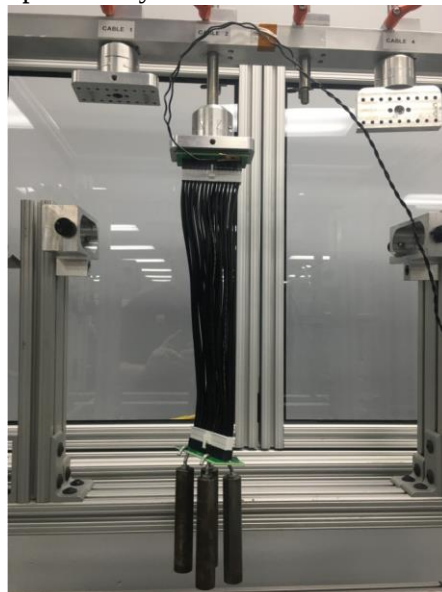


Fig. 3

90° Transverse Connector pull

CABLE DURABILITY:

- 1) Oscillate and monitor electrical continuity for open circuit indication.
 - a. $\pm 90^\circ$ Flex Mode, bend up to 500 cycles. load on cable end.

Fig. 4
(Setup picture)

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

LATCH PULL TEST:

- 1) Pull latch with specified tooling until it breaks. Record the maximum force.

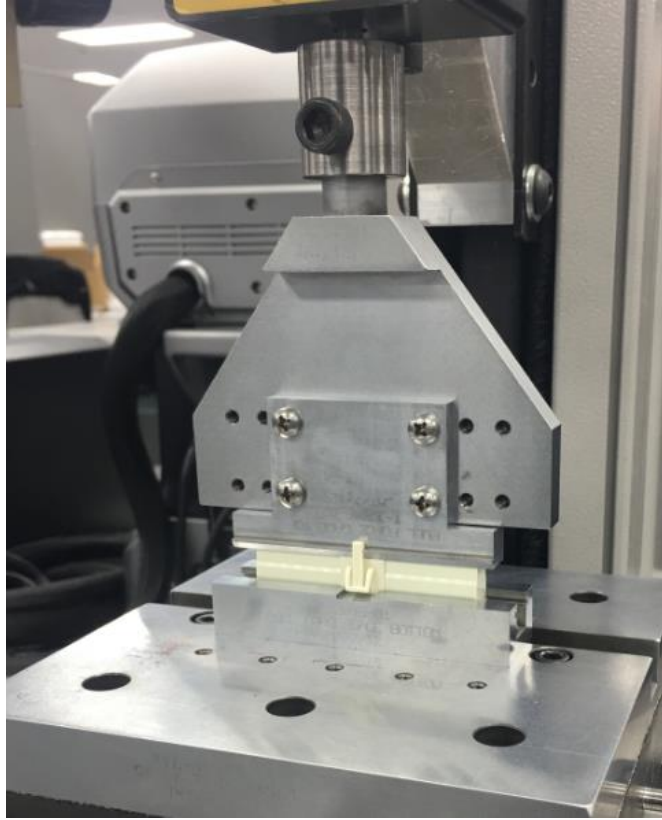


Fig. 5
(Setup picture)

RESULTS

Temperature Rise, CCC at a 20% de-rating

- CCC for a 30°C Temperature Rise-----8.8 A per contact with 2 contacts (2 x 1) powered
- CCC for a 30°C Temperature Rise-----7.2 A per contact with 4 contacts (2 x 2) powered
- CCC for a 30°C Temperature Rise-----7.0 A per contact with 6 contacts (2 x 3) powered
- CCC for a 30°C Temperature Rise-----6.4 A per contact with 8 contacts (2 x 4) powered
- CCC for a 30°C Temperature Rise-----5.5 A per contact with 30 contacts (2 x 15) powered

Mating – Unmating Forces

Thermal Aging Group

- Initial
 - Mating
 - Min -----19.45 lbs
 - Max-----24.67 lbs
 - Unmating
 - Min -----17.02 lbs
 - Max-----23.17 lbs
- After Thermal
 - Mating
 - Min -----21.14 lbs
 - Max-----24.60 lbs
 - Unmating
 - Min -----20.05 lbs
 - Max-----24.37 lbs

Mating/Unmating Durability Group

- Initial
 - Mating
 - Min -----22.86 lbs
 - Max-----28.17 lbs
 - Unmating
 - Min -----19.91 lbs
 - Max-----25.45 lbs
- After 25 Cycles
 - Mating
 - Min -----27.22 lbs
 - Max-----41.27 lbs
 - Unmating
 - Min -----20.63 lbs
 - Max-----33.32 lbs
- After Humidity
 - Mating
 - Min -----29.07 lbs
 - Max-----38.82 lbs
 - Unmating
 - Min -----19.18 lbs
 - Max-----33.78 lbs

RESULTS Continued**Mating/Unmating Basic (PMSD-02-18-K-06.00-S-XXX / IPBT-102-H1-T-D-K)**

- **Initial**
 - **Mating**
 - **Min** ----- 2.89 lbs
 - **Max** ----- 4.42 lbs
 - **Unmating**
 - **Min** ----- 2.56 lbs
 - **Max** ----- 3.54 lbs
- **After 25 Cycles**
 - **Mating**
 - **Min** ----- 3.86 lbs
 - **Max** ----- 5.83 lbs
 - **Unmating**
 - **Min** ----- 3.04 lbs
 - **Max** ----- 4.06 lbs
- **After 50 Cycles**
 - **Mating**
 - **Min** ----- 4.33 lbs
 - **Max** ----- 7.04 lbs
 - **Unmating**
 - **Min** ----- 3.60 lbs
 - **Max** ----- 4.48 lbs
- **After 75 Cycles**
 - **Mating**
 - **Min** ----- 4.37 lbs
 - **Max** ----- 7.07 lbs
 - **Unmating**
 - **Min** ----- 3.31 lbs
 - **Max** ----- 4.50 lbs
- **After 100 Cycles**
 - **Mating**
 - **Min** ----- 4.36 lbs
 - **Max** ----- 6.79 lbs
 - **Unmating**
 - **Min** ----- 3.44 lbs
 - **Max** ----- 4.31 lbs

RESULTS Continued**Mating/Unmating Basic (PMSD-08-18-K-06.00-S-XXX / IPBT-108-H1-T-D-K)**

- **Initial**
 - **Mating**
 - **Min** -----10.82 lbs
 - **Max** -----13.40 lbs
 - **Unmating**
 - **Min** ----- 9.47 lbs
 - **Max** -----13.21 lbs
- **After 25 Cycles**
 - **Mating**
 - **Min** -----13.94 lbs
 - **Max** -----16.64 lbs
 - **Unmating**
 - **Min** -----11.97 lbs
 - **Max** -----15.07 lbs
- **After 50 Cycles**
 - **Mating**
 - **Min** -----14.67 lbs
 - **Max** -----17.55 lbs
 - **Unmating**
 - **Min** -----13.84 lbs
 - **Max** -----16.16 lbs
- **After 75 Cycles**
 - **Mating**
 - **Min** -----16.26 lbs
 - **Max** -----17.26 lbs
 - **Unmating**
 - **Min** -----14.04 lbs
 - **Max** -----16.00 lbs
- **After 100 Cycles**
 - **Mating**
 - **Min** -----16.25 lbs
 - **Max** -----17.66 lbs
 - **Unmating**
 - **Min** -----13.26 lbs
 - **Max** -----15.41 lbs

Normal Force at 0.0130 inches deflection

- **Initial**
 - **Min** -----287.10 gf **Set** ---- 0.0001 inch
 - **Max** -----322.80 gf **Set** ---- 0.0009 inch
- **Thermal**
 - **Min** -----232.50 gf **Set** ---- 0.0017 inch
 - **Max** -----260.70 gf **Set** ---- 0.0036 inch

RESULTS Continued**Cable Pull force**

- **Group 1 0° Pull**
 - Min-----26.22 lbs
 - Max -----31.27 lbs
- **Group 2 90° Pull**
 - Min-----99.45 lbs
 - Max -----107.34 lbs
- **Group 3 90° Pull (Transverse)**
 - Min-----13.62 lbs
 - Max -----16.80 lbs

Insulation Resistance minimums, IR**Pin to Pin**

- **Initial**
 - Mated-----45000 Meg Ω ----- Passed
 - Unmated -----45000 Meg Ω ----- Passed
- **Thermal Shock**
 - Mated-----45000 Meg Ω ----- Passed
 - Unmated -----45000 Meg Ω ----- Passed
- **Humidity**
 - Mated----- 9000 Meg Ω ----- Passed
 - Unmated -----18300 Meg Ω ----- Passed

Row to Row

- **Initial**
 - Mated-----45000 Meg Ω ----- Passed
 - Unmated -----45000 Meg Ω ----- Passed
- **Thermal Shock**
 - Mated-----45000 Meg Ω ----- Passed
 - Unmated -----45000 Meg Ω ----- Passed
- **Humidity**
 - Mated----- 9000 Meg Ω ----- Passed
 - Unmated -----10500 Meg Ω ----- Passed

Dielectric Withstanding Voltage minimums, DWV

- **Minimums**
 - Test Voltage -----900 VAC

Pin to Pin

- **Initial DWV** -----Passed
- **Thermal DWV** -----Passed
- **Humidity DWV** -----Passed

Row to Row

- **Initial DWV** -----Passed
- **Thermal DWV** -----Passed
- **Humidity DWV** -----Passed

RESULTS Continued**Cable Flex:****Insulation Resistance minimums, IR****Pin to Pin**

- **Initial**
 - **Mated**-----45000 Meg Ω ----- Passed
- **After 500 flex cycles**
 - **Mated**-----45000 Meg Ω ----- Passed

Row to Row

- **Initial**
 - **Mated**-----45000 Meg Ω ----- Passed
- **After 500 flex cycles**
 - **Mated**-----45000 Meg Ω ----- Passed

Dielectric Withstanding Voltage minimums, DWV

- **Test Voltage**-----900 VAC

Pin to Pin

- **Initial DWV** -----Passed
- **After 500 Flex cycles DWV** -----Passed

Row to Row

- **Initial DWV** -----Passed
- **After 500 Flex cycles DWV** -----Passed

Latch pull test:

- **Group 1 After 250 cycles**
 - **Min**-----16.97 lbs
 - **Max** -----17.66 lbs
- **Group 2 After thermal aging and 250 cycles**
 - **Min**-----17.21 lbs
 - **Max** -----18.02 lbs

RESULTS Continued**LLCR Gas Tight (192 LLCR test points)**

- Initial -----7.88 mOhms Max
- Gas-Tight
 - ≤ +5.0 mOhms -----188 Points ----- Stable
 - +5.1 to +10.0 mOhms -----3 Points ----- Minor
 - +10.1 to +15.0 mOhms -----1 Points ----- Acceptable
 - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
 - +50.1 to +1000 mOhms -----0 Points ----- Unstable
 - >+1000 mOhms -----0 Points ----- Open Failure

LLCR Thermal Aging (192 LLCR test points)

- Initial -----7.85 mOhms Max
- Thermal Aging
 - ≤ +5.0 mOhms -----179 Points ----- Stable
 - +5.1 to +10.0 mOhms -----10 Points ----- Minor
 - +10.1 to +15.0 mOhms -----3 Points ----- Acceptable
 - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
 - +50.1 to +1000 mOhms -----0 Points ----- Unstable
 - >+1000 mOhms -----0 Points ----- Open Failure

LLCR Durability (192 LLCR test points)

- Initial -----7.77 mOhms Max
- Durability, 25 Cycles
 - ≤ +5.0 mOhms -----192 Points ----- Stable
 - +5.1 to +10.0 mOhms -----0 Points ----- Minor
 - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
 - +50.1 to +1000 mOhms -----0 Points ----- Unstable
 - >+1000 mOhms -----0 Points ----- Open Failure
- Thermal
 - ≤ +5.0 mOhms -----187 Points ----- Stable
 - +5.1 to +10.0 mOhms -----4 Points ----- Minor
 - +10.1 to +15.0 mOhms -----1 Points ----- Acceptable
 - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
 - +50.1 to +1000 mOhms -----0 Points ----- Unstable
 - >+1000 mOhms -----0 Points ----- Open Failure
- Humidity
 - ≤ +5.0 mOhms -----192 Points ----- Stable
 - +5.1 to +10.0 mOhms -----0 Points ----- Minor
 - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
 - +50.1 to +1000 mOhms -----0 Points ----- Unstable
 - >+1000 mOhms -----0 Points ----- Open Failure

RESULTS Continued

LLCR Shock & Vibration (192 LLCR test points)

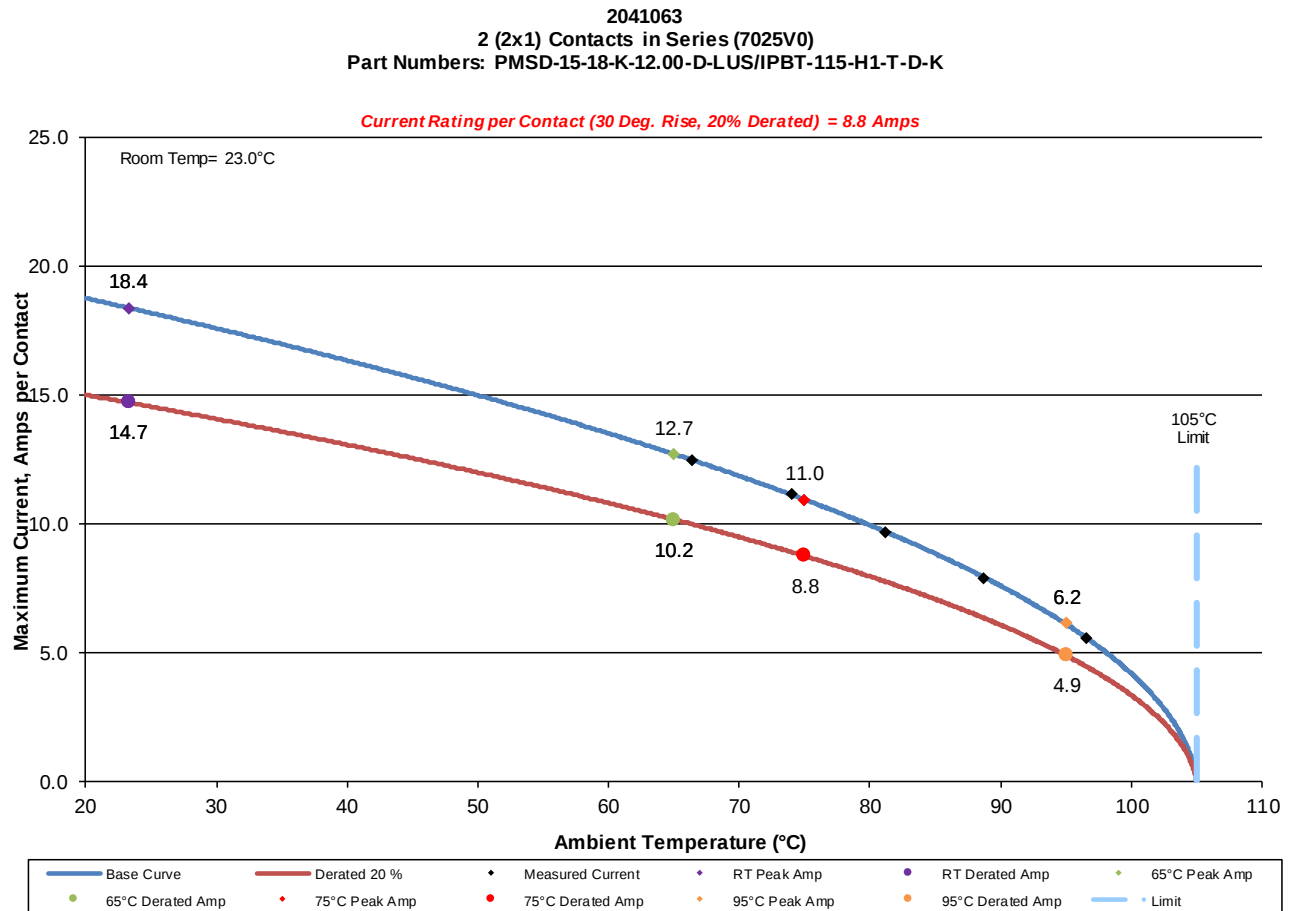
- **Initial** -----9.59 mOhms Max
- **Shock & Vibration**
 - **<= +5.0 mOhms**-----192 Points ----- Stable
 - **+5.1 to +10.0 mOhms**-----0 Points ----- Minor
 - **+10.1 to +15.0 mOhms** -----0 Points ----- Acceptable
 - **+15.1 to +50.0 mOhms** -----0 Points ----- Marginal
 - **+50.1 to +1000 mOhms**-----0 Points ----- Unstable
 - **>+1000 mOhms**-----0 Points ----- Open Failure

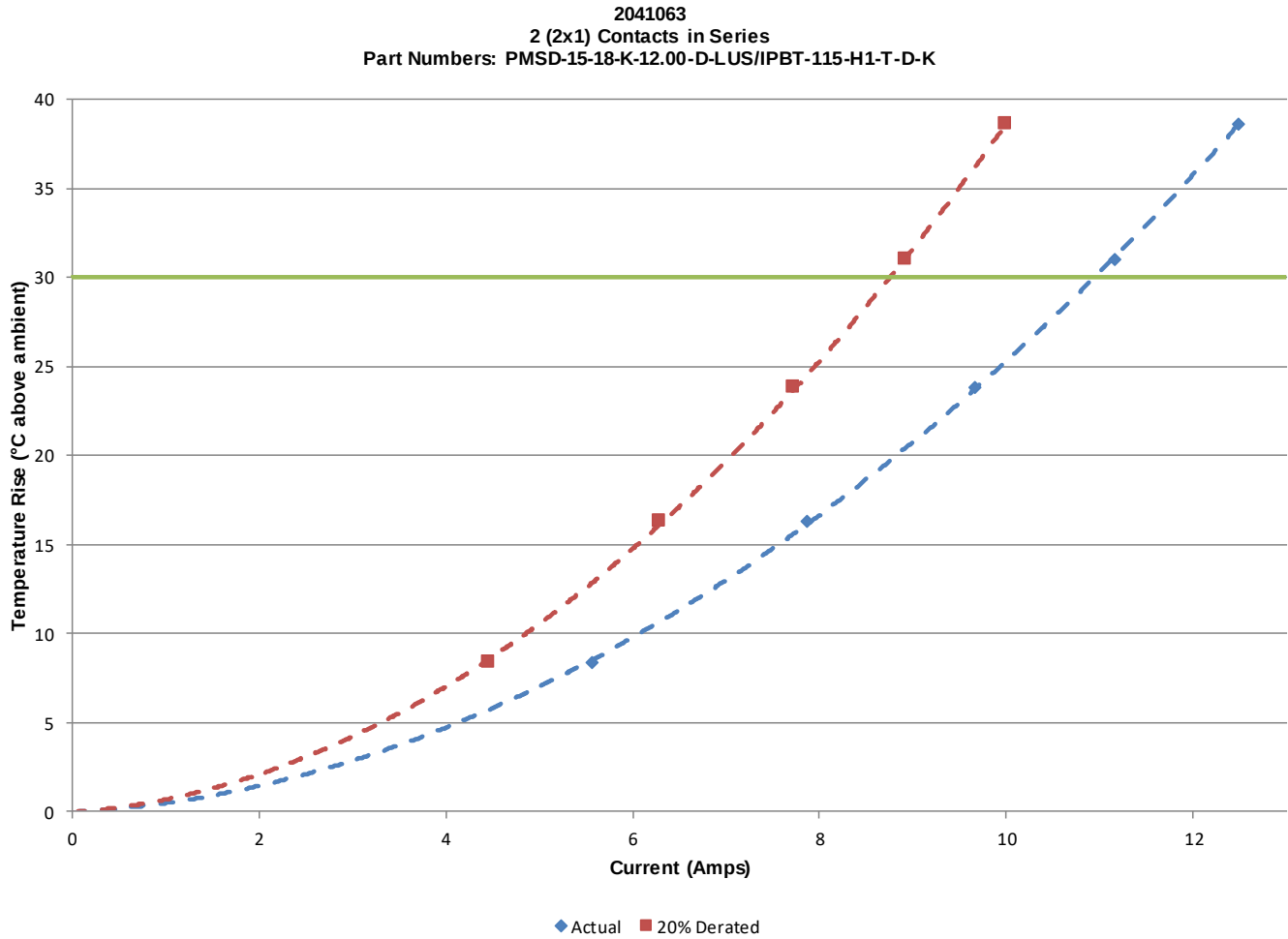
Mechanical Shock & Random Vibration:

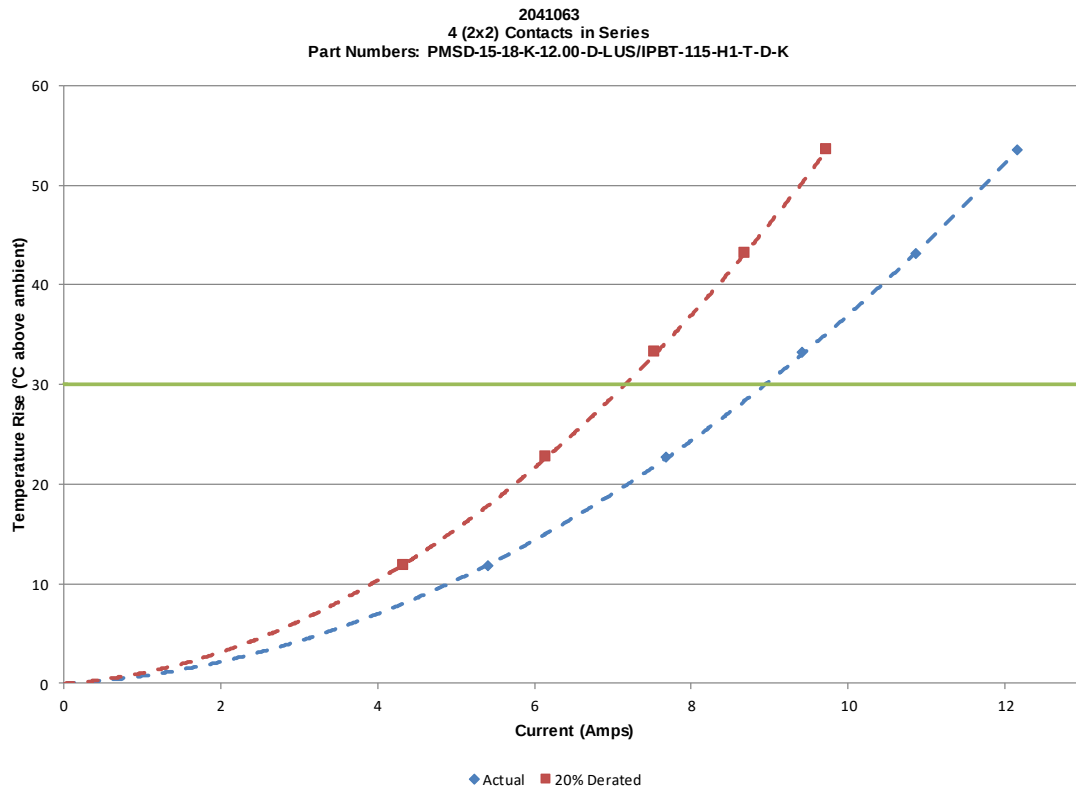
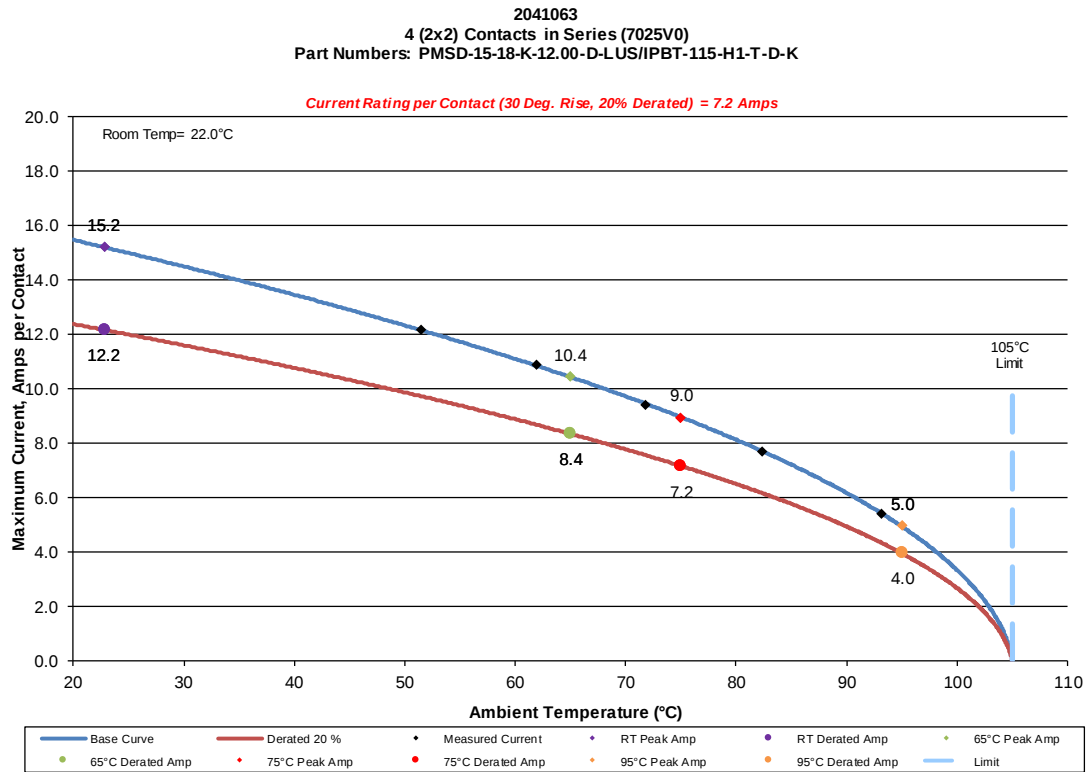
- **Shock**
 - **No Damage**----- Pass
 - **50 Nanoseconds** ----- Pass
- **Vibration**
 - **No Damage**----- Pass
 - **50 Nanoseconds** ----- Pass

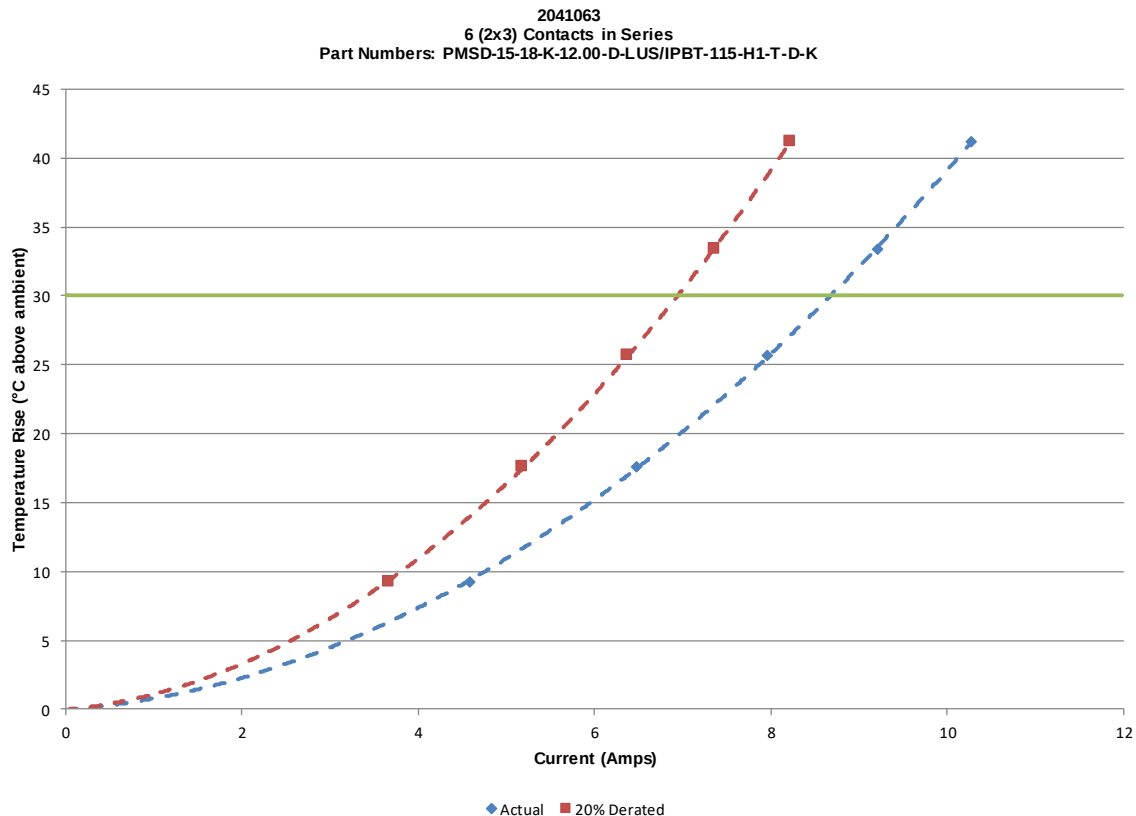
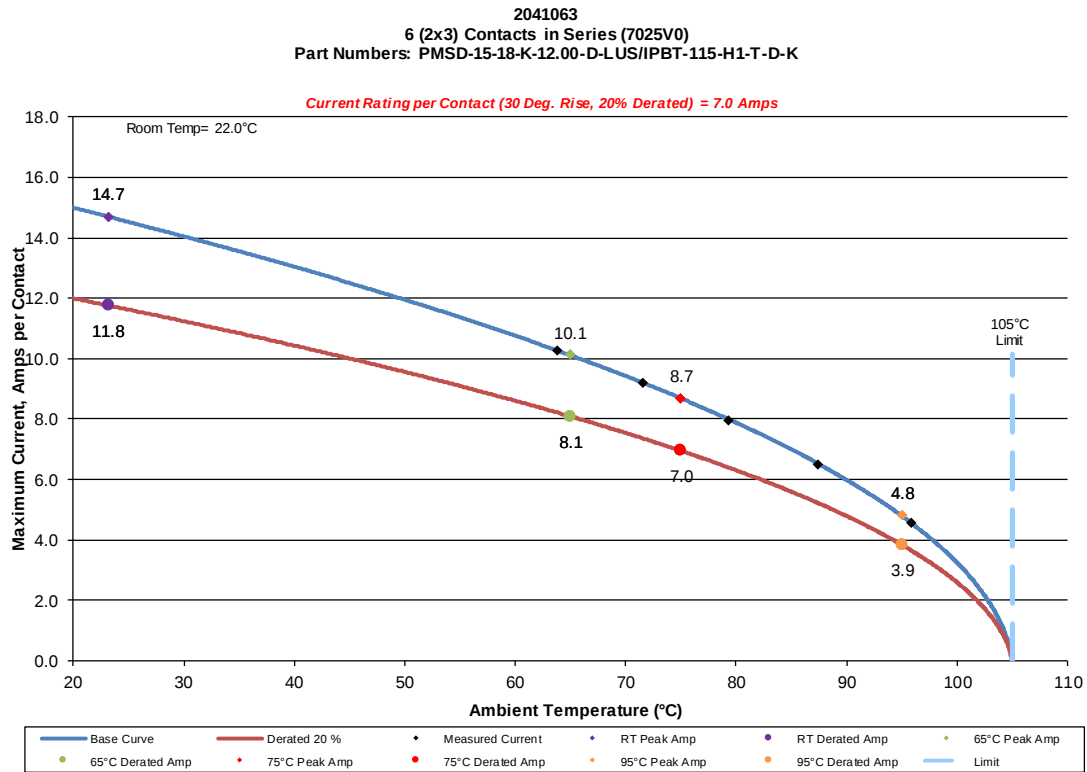
DATA SUMMARIES**TEMPERATURE RISE (Current Carrying Capacity, CCC):**

- 1) High quality thermocouples whose temperature slopes track one another were used for temperature monitoring.
- 2) The thermocouples were placed at a location to sense the maximum temperature generated during testing.
- 3) Temperature readings recorded are those for which three successive readings, 15 minutes apart, differ less than 1° C (computer controlled data acquisition).
- 4) Adjacent contacts were powered:
 - a. Linear configuration with 2 adjacent conductors/contacts powered



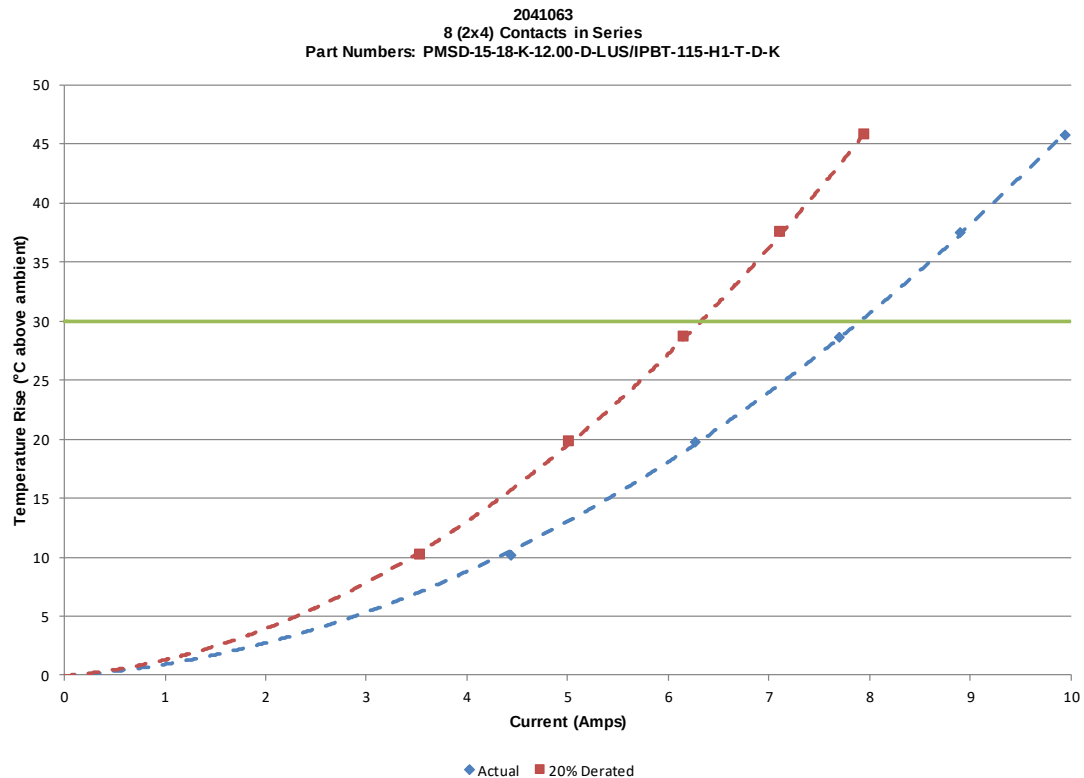
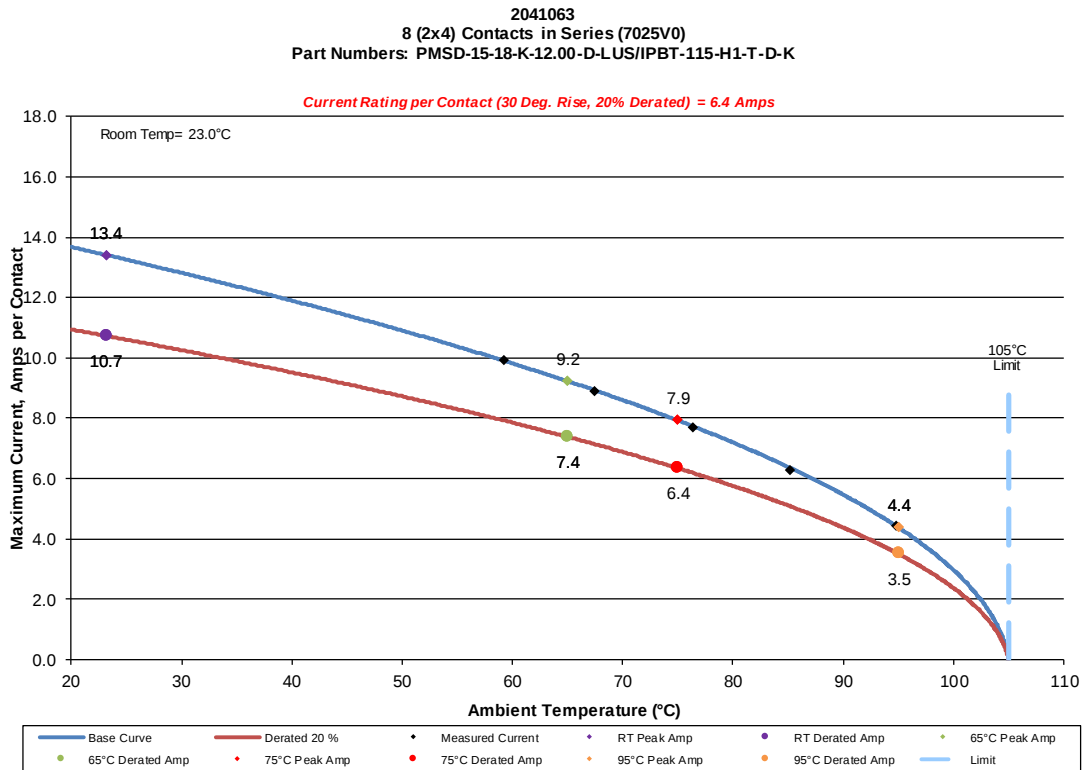


DATA SUMMARIES Continued**b. Linear configuration with 4 adjacent conductors/contacts powered**

DATA SUMMARIES Continued**c. Linear configuration with 6 adjacent conductors/contacts powered**

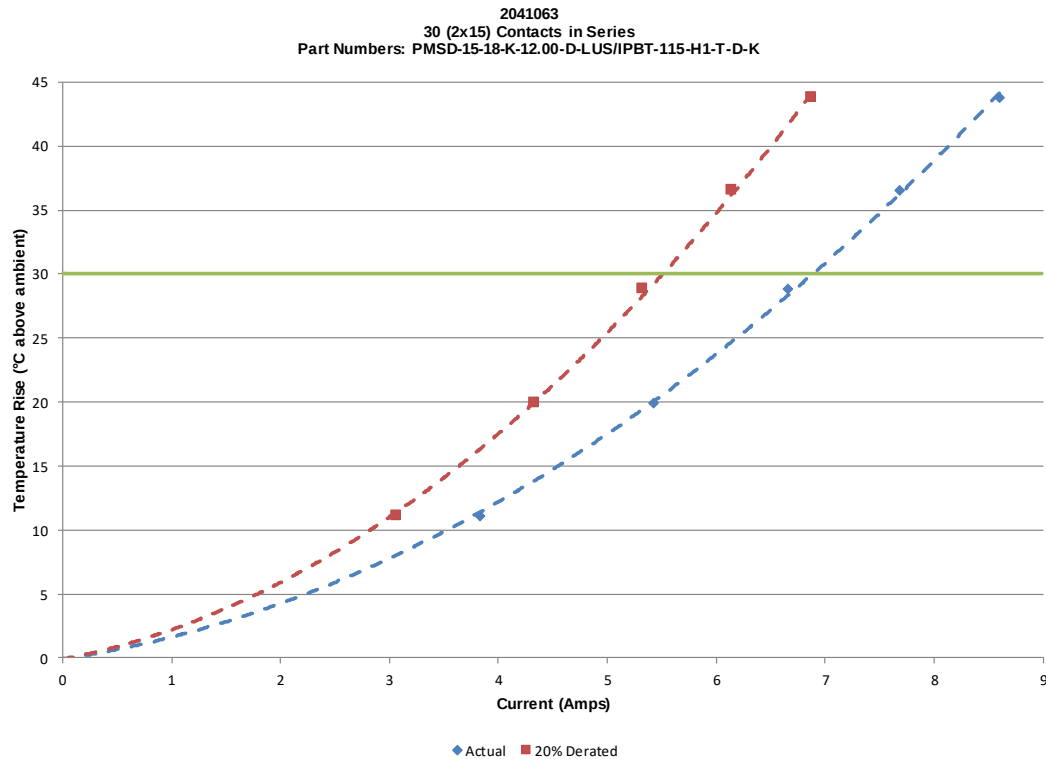
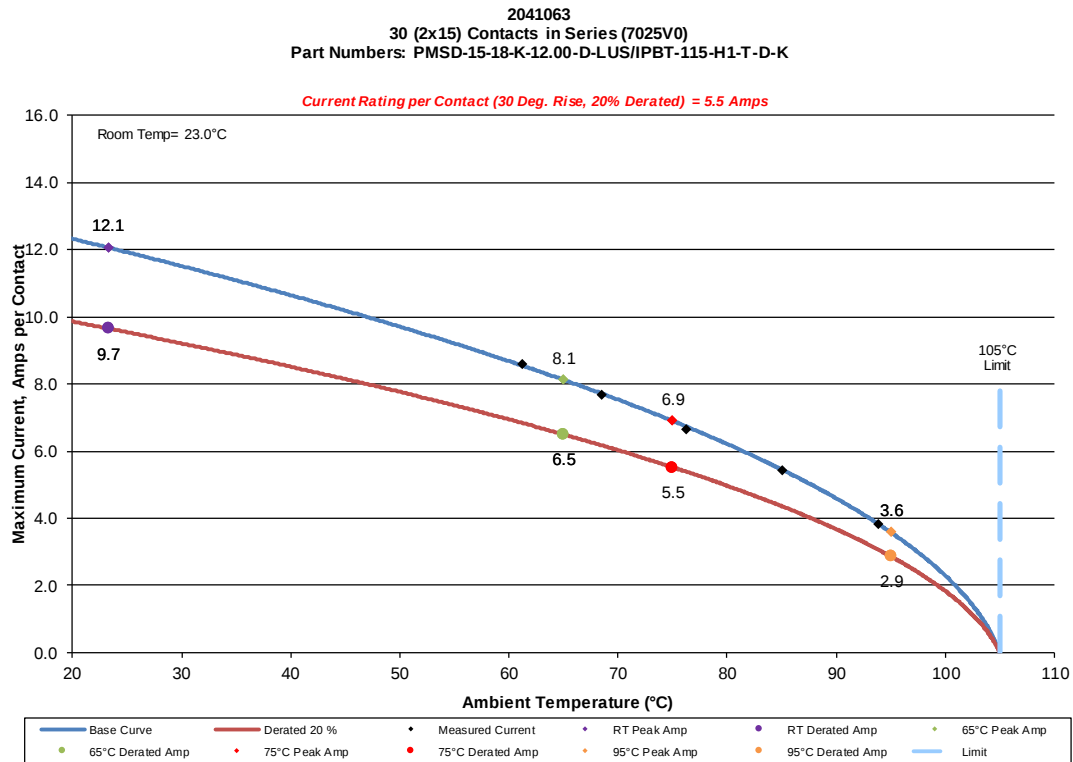
DATA SUMMARIES Continued

d. Linear configuration with 8 adjacent conductors/contacts powered



DATA SUMMARIES Continued

e. Linear configuration with 30 adjacent conductors/contacts powered



DATA SUMMARIES Continued**MATING/UNMATING:****Thermal Aging Group**

	Initial				After Thermals			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	86.50	19.45	75.69	17.02	94.03	21.14	89.18	20.05
Maximum	109.71	24.67	103.06	23.17	109.42	24.60	108.40	24.37
Average	98.84	22.22	92.72	20.85	98.30	22.10	96.49	21.69
St Dev	6.34	1.43	8.06	1.81	5.22	1.17	6.10	1.37
Count	8	8	8	8	8	8	8	8

Mating/Unmating Durability Group

	Initial				25 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	101.67	22.86	88.56	19.91	121.05	27.22	91.78	20.63
Maximum	125.30	28.17	113.19	25.45	183.59	41.27	148.23	33.32
Average	111.97	25.17	101.49	22.82	145.43	32.70	118.12	26.56
St Dev	9.00	2.02	9.13	2.05	22.43	5.04	17.53	3.94
Count	8	8	8	8	8	8	8	8

	After Humidity			
	Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	129.30	29.07	85.31	19.18
Maximum	172.67	38.82	150.25	33.78
Average	141.29	31.77	122.84	27.62
St Dev	15.49	3.48	19.70	4.43
Count	8	8	8	8

DATA SUMMARIES Continued**Mating/Unmating Basic (PMSD-02-18-K-06.00-S-XXX / IPBT-102-H1-T-D-K)**

	Initial				25 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	12.85	2.89	11.39	2.56	17.17	3.86	13.52	3.04
Maximum	19.66	4.42	15.75	3.54	25.93	5.83	18.06	4.06
Average	14.52	3.27	13.12	2.95	20.19	4.54	15.68	3.53
St Dev	2.20	0.50	1.47	0.33	3.09	0.70	1.56	0.35
Count	8	8	8	8	8	8	8	8
	50 Cycles				75 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	19.26	4.33	16.01	3.60	19.44	4.37	14.72	3.31
Maximum	31.31	7.04	19.93	4.48	31.45	7.07	20.02	4.50
Average	22.57	5.07	17.27	3.88	22.66	5.09	16.88	3.80
St Dev	4.02	0.90	1.31	0.29	3.94	0.89	1.64	0.37
Count	8	8	8	8	8	8	8	8
	100 Cycles							
	Mating		Unmating					
	Newtons	Force (Lbs)	Newtons	Force (Lbs)				
Minimum	19.39	4.36	15.30	3.44				
Maximum	30.20	6.79	19.17	4.31				
Average	22.65	5.09	16.74	3.76				
St Dev	3.57	0.80	1.48	0.33				
Count	8	8	8	8				

DATA SUMMARIES Continued**Mating/Unmating Basic (PMSD-08-18-K-06.00-S-XXX / IPBT-108-H1-T-D-K)**

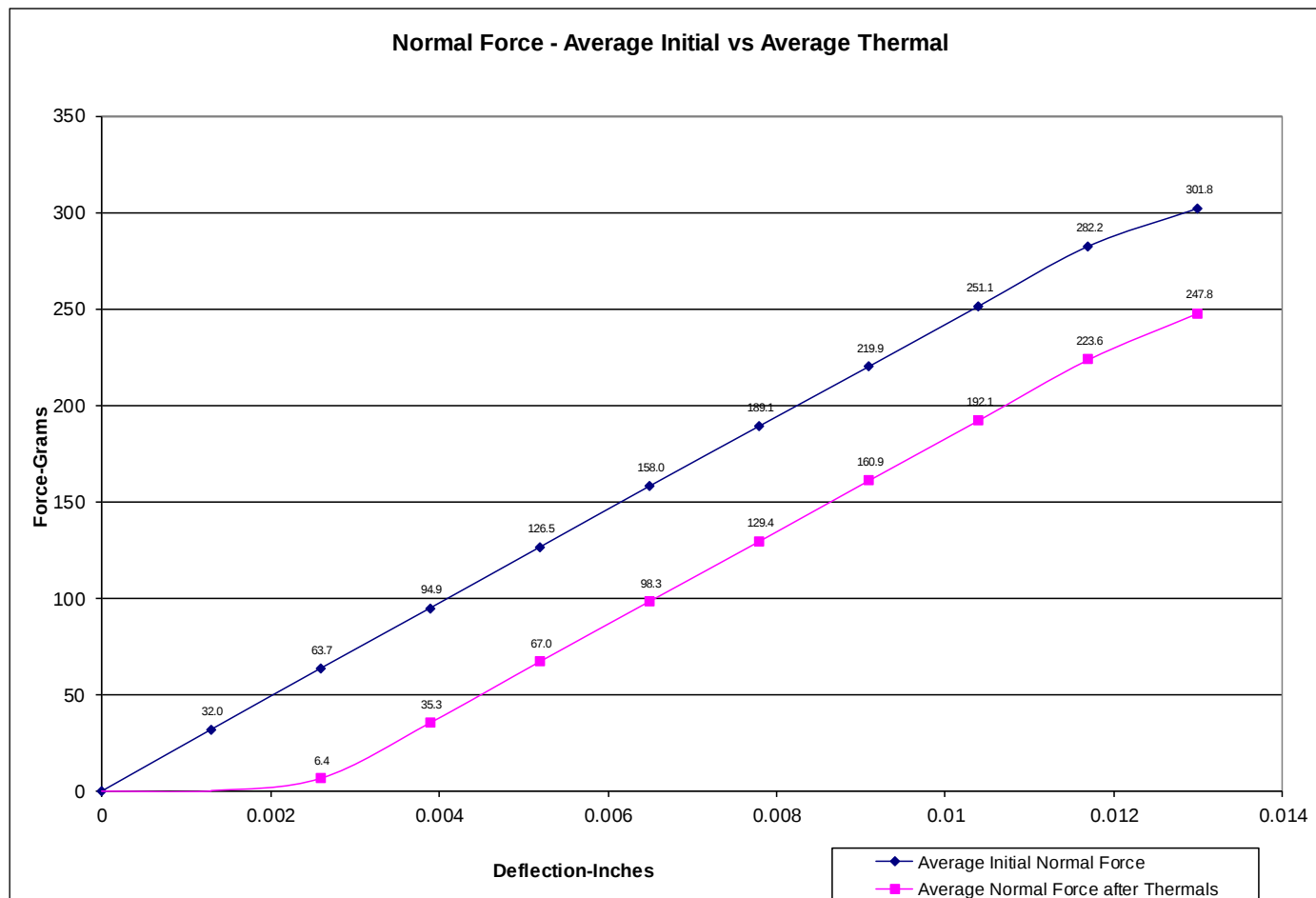
	Initial				25 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	48.13	10.82	42.12	9.47	62.01	13.94	53.24	11.97
Maximum	59.60	13.40	58.76	13.21	74.01	16.64	67.03	15.07
Average	54.31	12.21	52.68	11.84	66.86	15.03	60.18	13.53
St Dev	3.57	0.80	4.92	1.11	3.90	0.88	5.57	1.25
Count	8	8	8	8	8	8	8	8
	50 Cycles				75 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	65.25	14.67	61.56	13.84	72.32	16.26	62.45	14.04
Maximum	78.06	17.55	71.88	16.16	76.77	17.26	71.17	16.00
Average	71.96	16.18	65.78	14.79	74.48	16.74	66.83	15.02
St Dev	4.42	0.99	3.28	0.74	1.42	0.32	3.48	0.78
Count	8	8	8	8	8	8	8	8
	100 Cycles							
	Mating		Unmating					
	Newtons	Force (Lbs)	Newtons	Force (Lbs)				
Minimum	72.28	16.25	58.98	13.26				
Maximum	78.55	17.66	68.54	15.41				
Average	75.13	16.89	63.42	14.26				
St Dev	2.62	0.59	3.93	0.88				
Count	8	8	8	8				

DATA SUMMARIES Continued**NORMAL FORCE (FOR CONTACTS TESTED OUTSIDE THE HOUSING):**

- 1) Calibrated force gauges are used along with computer-controlled positioning equipment.
- 2) Typically, 8-10 readings are taken and the averages reported.

Initial	Deflections in inches Forces in Grams										
	<u>0.0013</u>	<u>0.0026</u>	<u>0.0039</u>	<u>0.0052</u>	<u>0.0065</u>	<u>0.0078</u>	<u>0.0091</u>	<u>0.0104</u>	<u>0.0117</u>	<u>0.0130</u>	<u>SET</u>
Averages	31.99	63.69	94.93	126.48	158.03	189.08	219.91	251.13	282.17	301.83	0.0005
Min	29.30	60.10	88.90	120.20	150.00	180.30	210.30	240.00	268.00	287.10	0.0001
Max	37.90	73.50	109.80	143.90	177.10	208.30	239.10	272.70	302.00	322.80	0.0009
St. Dev	2.443	3.679	5.466	6.420	7.375	7.940	8.762	10.333	11.333	11.473	0.0002
Count	12	12	12	12	12	12	12	12	12	12	12

After Thermals	Deflections in inches Forces in Grams										
	<u>0.0013</u>	<u>0.0026</u>	<u>0.0039</u>	<u>0.0052</u>	<u>0.0065</u>	<u>0.0078</u>	<u>0.0091</u>	<u>0.0104</u>	<u>0.0117</u>	<u>0.0130</u>	<u>SET</u>
Averages	0.02	6.38	35.25	67.02	98.26	129.36	160.94	192.09	223.64	247.76	0.0027
Min	0.00	0.00	20.80	54.20	88.10	119.30	150.10	178.10	207.90	232.50	0.0017
Max	0.20	25.10	56.10	85.70	116.10	145.90	176.40	207.30	237.10	260.70	0.0036
St. Dev	0.060	8.843	11.069	10.053	9.736	10.047	9.610	10.011	9.992	9.686	0.0005
Count	11	11	11	11	11	11	11	11	11	11	11



DATA SUMMARIES Continued**INSULATION RESISTANCE (IR):**

Pin to Pin			
	Mated	Unmated	Unmated
Minimum	PMSD/IPBT	PMSD	IPBT
Initial	45000	45000	45000
Thermal	45000	45000	45000
Humidity	9000	18300	45000

Row to Row			
	Mated	Unmated	Unmated
Minimum	PMSD/IPBT	PMSD	IPBT
Initial	45000	45000	45000
Thermal	45000	45000	45000
Humidity	9000	10500	45000

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

Voltage Rating Summary	
Minimum	PMSD/IPBT
Test Voltage	900

Pin to Pin	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

Row to Row	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

DATA SUMMARIES Continued**Cable Pull Force:****Group 1 0° Pull**

	Force (lbs)
Minimum	26.22
Maximum	31.27
Average	28.46

Group 2 90° Pull

	Force (lbs)
Minimum	99.45
Maximum	107.34
Average	103.56

Group 3 90° Pull (Transverse)

	Force (lbs)
Minimum	13.62
Maximum	16.80
Average	15.27

DATA SUMMARIES Continued**Cable Flex:****Insulation Resistance minimums, IR**

Pin to Pin	
Mated	
Minimum	
Initial	45000
After 500 Flex Cycles	45000

Row to Row	
Mated	
Minimum	
Initial	45000
After 500 Flex Cycles	45000

Dielectric Withstanding Voltage minimums, DWV

Voltage Rating Summary	
Minimum	PMSD/IPBT
Test Voltage	900

Pin to Pin	
Initial Test Voltage	Passed
After 500 Flex Cycles Test Voltage	Passed

Row to Row	
Initial Test Voltage	Passed
After 500 Flex Cycles Test Voltage	Passed

Latch pull test**Group 1**

	Force (lbs)
Minimum	16.97
Maximum	17.66
Average	17.36
Count	10

Group 2

	Force (lbs)
Minimum	17.21
Maximum	18.02
Average	17.70
Count	10

DATA SUMMARIES Continued**LLCR Durability:**

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: -----Stable
 - b. $+5.1$ to $+10.0$ mOhms: -----Minor
 - c. $+10.1$ to $+15.0$ mOhms: -----Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: -----Marginal
 - e. $+50.1$ to $+1000$ mOhms: -----Unstable
 - f. $>+1000$ mOhms: -----Open Failure

LLCR Measurement Summaries by Pin Type				
Date	8/29/2019	12/3/2019	12/18/2019	1/3/2020
Room Temp (Deg C)	23	23	22	22
Rel Humidity (%)	48	28	38	43
Technician	John Crawford	John Crawford	John Crawford	John Crawford
mOhm values	Actual Initial	Delta 25 Cycles	Delta Therm Shck	Delta Humidity
Pin Type 1: Signal				
Average	5.06	0.72	1.03	0.57
St. Dev.	0.50	0.55	1.50	0.61
Min	4.35	0.02	0.01	0.00
Max	7.77	3.38	12.22	2.96
Summary Count	192	192	192	192
Total Count	192	192	192	192

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	$>5 \text{ \& } \leq 10$	$>10 \text{ \& } \leq 15$	$>15 \text{ \& } \leq 50$	$>50 \text{ \& } \leq 1000$	>1000
25 Cycles	192	0	0	0	0	0
Therm Shck	187	4	1	0	0	0
Humidity	192	0	0	0	0	0

DATA SUMMARIES Continued**LLCR Thermal Aging:**

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: -----Stable
 - b. $+5.1$ to $+10.0$ mOhms: -----Minor
 - c. $+10.1$ to $+15.0$ mOhms: -----Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: -----Marginal
 - e. $+50.1$ to $+1000$ mOhms: -----Unstable
 - f. $>+1000$ mOhms: -----Open Failure

LLCR Measurement Summaries by Pin Type				
Date	10/24/2019	11/25/2019		
Room Temp (Deg C)	23	22		
Rel Humidity (%)	37	34		
Technician	John Crawford	John Crawford		
mOhm values	Actual Initial	Delta Thermal	Delta	Delta
Pin Type 1: Signal				
Average	5.15	1.31		
St. Dev.	0.69	2.11		
Min	4.29	0.01		
Max	7.85	13.60		
Summary Count	192	192		
Total Count	192	192		

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	$>5 \text{ \& } \leq 10$	$>10 \text{ \& } \leq 15$	$>15 \text{ \& } \leq 50$	$>50 \text{ \& } \leq 1000$	>1000
Thermal	179	10	3	0	0	0

DATA SUMMARIES Continued**LLCR Gas Tight:**

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: -----Stable
 - b. $+5.1$ to $+10.0$ mOhms: -----Minor
 - c. $+10.1$ to $+15.0$ mOhms: -----Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: -----Marginal
 - e. $+50.1$ to $+1000$ mOhms: -----Unstable
 - f. $>+1000$ mOhms: -----Open Failure

LLCR Measurement Summaries by Pin Type				
Date	8/9/2019	11/5/2019		
Room Temp (Deg C)	23	22		
Rel Humidity (%)	51	38		
Technician	John Crawford	John Crawford		
mOhm values	Actual Initial	Delta Acid Vapor	Delta	Delta
Pin Type 1: Signal				
Average	5.03	0.70		
St. Dev.	0.49	1.16		
Min	4.38	0.01		
Max	7.88	11.70		
Summary Count	192	192		
Total Count	192	192		

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	$>5 \text{ \& } \leq 10$	$>10 \text{ \& } \leq 15$	$>15 \text{ \& } \leq 50$	$>50 \text{ \& } \leq 1000$	>1000
Acid Vapor	188	3	1	0	0	0

DATA SUMMARIES Continued**LLCR Shock &Vibration:**

- 1). A total of 192 points were measured.
- 2). EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3). The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: -----Stable
 - b. $+5.1$ to $+10.0$ mOhms: -----Minor
 - c. $+10.1$ to $+15.0$ mOhms: -----Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: -----Marginal
 - e. $+50.1$ to $+1000$ mOhms -----Unstable
 - f. $>+1000$ mOhms: -----Open Failure

LLCR Measurement Summaries by Pin Type				
Date	8/9/2019	10/24/2019		
Room Temp (Deg C)	23	23		
Rel Humidity (%)	51	39		
Technician	John Crawford	John Crawford		
mOhm values	Actual	Delta	Delta	Delta
	Initial	Shock-Vib		
Pin Type 1: Signal				
Average	7.64	0.41		
St. Dev.	0.32	0.49		
Min	7.17	0.00		
Max	9.59	3.79		
Summary Count	192	192		
Total Count	192	192		

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	$>5 \text{ \& } \leq 10$	$>10 \text{ \& } \leq 15$	$>15 \text{ \& } \leq 50$	$>50 \text{ \& } \leq 1000$	>1000
Shock-Vib	192	0	0	0	0	0

Nanosecond Event Detection:

Shock and Vibration Event Detection Summary	
Contacts tested	60
Test Condition	C, 100g's, 6ms, Half-Sine
Shock Events	0
Test Condition	V-B, 7.56 rms g
Vibration Events	0
Total Events	0

EQUIPMENT AND CALIBRATION SCHEDULES**Equipment #:** TCT-04**Description:** Dillon Quantrol TC21 25-1000 mm/min series test stand**Manufacturer:** Dillon Quantrol**Model:** TC2 I series test stand**Serial #:** 04-1041-04**Accuracy:** Speed Accuracy: +/- 5% of indicated speed; Speed Accuracy: +/- 5% of indicated speed;
... Last Cal: 05/29/2019, Next Cal: 05/29/2020**Equipment #:** MO-11**Description:** Switch/Multimeter**Manufacturer:** Keithley**Model:** 3706**Serial #:** 120169**Accuracy:** See Manual

... Last Cal: 09/11/2019, Next Cal: 09/11/2020

Equipment #: THC-05**Description:** Temperature/Humidity Chamber (Chamber Room)**Manufacturer:** Thermotron**Model:** SM-8-3800**Serial #:** 05 23 00 02**Accuracy:** See Manual

... Last Cal: 11/14/2019, Next Cal: 11/14/2020

Equipment #: TSC-01**Description:** Vertical Thermal Shock Chamber**Manufacturer:** Cincinnati Sub Zero**Model:** VTS-3-6-6-SC/AC**Serial #:** 10-VT14993**Accuracy:** See Manual

... Last Cal: 06/30/2019, Next Cal: 06/30/2020

Equipment #: HPT-01**Description:** Hipot Safety Tester**Manufacturer:** Vitrek**Model:** V73**Serial #:** 019808**Accuracy:**

... Last Cal: 05/15/2019, Next Cal: 05/15/2020

Equipment #: PS-02**Description:** Power Supply**Manufacturer:** Hewlett-Packard**Model:** 6033A**Serial #:** N/A**Accuracy:** See Manual

... Last Cal: NOT CALIBRATED

EQUIPMENT AND CALIBRATION SCHEDULES**Equipment #:** SVC-01**Description:** Shock & Vibration Table**Manufacturer:** Data Physics**Model:** LE-DSA-10-20K**Serial #:** 10037**Accuracy:** See Manual

... Last Cal: 04/22/2019, Next Cal: 04/22/2020

Equipment #: ACLM-01**Description:** Accelerometer**Manufacturer:** PCB Piezotronics**Model:** 352C03**Serial #:** 115819**Accuracy:** See Manual

... Last Cal: 07/18/2019, Next Cal: 07/18/2020

Equipment #: ED-03**Description:** Event Detector**Manufacturer:** Analysis Tech**Model:** 32EHD**Serial #:** 1100604**Accuracy:** See Manual

... Last Cal: 10/31/2019, Next Cal: 10/31/2020

Equipment #: MO-04**Description:** Multimeter /Data Acquisition System**Manufacturer:** Keithley**Model:** 2700**Serial #:** 0798688**Accuracy:** See Manual

... Last Cal: 09/11/2019, Next Cal: 09/11/2020